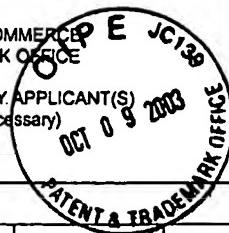


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ATTY DOCKET NO.

03500.010106.5

APPLICATION NO.

10/615,995

APPLICANT

Toshikazu Ohnishi et al.

FILING DATE

July 10, 2003

GROUP

2879
NYA

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
JW	6,147,449	11/14/00	Iwasaki et al.	313	495	
JW	6,171,162 B1	01/09/01	Iwasaki et al.	445	6	
JW	6,169,356 B1	01/02/01	Ohnishi et al.	313	495	
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JW	1069828 A	3/10/93	China	H01J	19/42	Abst.,Trans. & EP 0 513 777
JW	1-031332	02/01/89	Japan	H01J	29/48	Abst.
JW	0 513 777 A2	11/19/92	EPO	H01J	1/30	English

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER

Joseph Williams

DATE CONSIDERED

3/3/04

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*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>JW</i>		6,348,761 B1	2/02	Nomura et al.	313	495	6/94
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<i>JW</i>		5,066,883	11/91	Yoshioka et al.	313	309	
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<i>JW</i>		1-309242	12/89	JAPAN			Translation
<i>JW</i>		0 299 461	1/89	EPO			
EXAMINER <i>Joseph Williams</i>			DATE CONSIDERED		3/3/04		

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<i>JW</i>	"Metal Influence on Switching MIM Diodes", H. Pagnia, et al., Phys. Stat. Sol. (a), 111, 387 (1989)		
<i>JW</i>	"Scanning Tunnelling Microscopic Investigations of Electroformed Planar Metal-Insulator-Metal Diodes," H. Pagnia, N. Sotnik and W. Wirth, Int. J. Electronics, Vol. 69, No. 1, 25-32 (1990)		
<i>JW</i>	"Energy Distribution of Emitted Electrons from Electroformed MIM Structures: The Carbon Island Model," M. Bischoff, H. Pagnia and J. Trickl, Int. J. Electronics, Vol. 73, No. 5, 1009-1010 (1992)		
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<i>JW</i>	"On the Electron Emission from Evaporated Thin Au Films," M. Bischoff, R. Holzer and H. Pagnia, Physics Letters, Vol. 62A, No. 7 (October 3, 1977)		
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<i>fw</i>		M.I. Elinson "The Emission of Hot Electrons and the Field Emission of Electrons from Tin Oxide," Radio Engineering and Electronic Physics, (1965), pp. 1290-1296	
<i>fw</i>		G. Dittner, "Electrical Conduction and Electron Emission of Discontinuous Thin Films," Thin Solid Films, 9, (1972) pp. 317-328	
<i>fw</i>		H. Hartwell, et al, "Strong Electron Emission From Patterned Tin-Indium Oxide Thin Films," Int'l Electron Devices Meeting (1975) pp. 519-521	
<i>fw</i>		M. Araki, "Electroforming and Electron Emission of Carbon Thin Films," J. Vac. Soc. Japan, 26, (1983) pp. 22-29	
<i>fw</i>		"Carbon-Nanoslit Model for the Electroforming Process in MIM Structures," M. Bischoff, Int. J. Electronics, Vol. 70, No. 3, 491-498 (1991)	
<i>fw</i>		Patent Abstracts of Japan, vol. 14, no. 1 08 (E-896) (4051), Feb 27, 1990	
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